



iRel40

Intelligent Reliability along the value chain

Challenges and objectives



Reliability is a major enabler for European products and promotes sustainability. Objectives of iRel40 were improving reliability along the **value chain chip-package-board/system** through modeling and simulation, through deepened understanding based on physics of failure, using new materials and designs for reliability, implementing real-time feedback in production lines, enhancing test methods, developing predictive algorithms and the use of all available data to learn faster through AI and ML.

Technical results

- Results from 34 use cases and more than 200 test vehicles were shared
- The usage of **digital twin** methods and behavioral models during the early stages of a design phase enables the virtual examination of different operational or environmental conditions
- Earlier recognition of possible issues regarding the reliability of later products can be used as starting point for **virtual investigation** of improvements (e.g. cost reduction for changes, early design decision)

intelligent Reliability 4.0

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- In general **equipment data are more relevant** than pure process data (related to failure rate)
- Preassembly (dicing & grinding) is crucial to reach reliable packaged dies
- Impact in one domain has impact in other domain (Single Device Tracking overall manufacturing domains applying AI)
- Avoid human dependent triggering of corrective actions
- Importance of materials and material data (e.g. purity of package materials)
- Artificial intelligence, machine learning methodologies and good data quality are important enablers.

Benefit of device tracking: there is no package problem, but a test problem => yield, cost

eWLB wafer maps show stripes and random distributed fails



Reconstructed frontend

wafer map

Fails mainly come from devices at the edge of frontend wafers

iRel40 is building bridges





Impact



New Products

New Processes 60 New Methods 155

iRel40 Dissemination

Nano 2022

> 100 publications in international

78 partners	developed	developed	developed	 journals and conferences > 100 presentations at international 	
34	Process Time > 10	Form Factor > 50%	Fabs > 15	conferences and workshops • <i>iRel40 book</i> published in	Willem Dirk van Driel Klaus Pressel Mujdat Soyturk <i>Editors</i>
use cases > 200 test vehicles	times faster	reduction in volume while keeping automotive reliability	reliability results entered into more than 15 fabs in Europe (wafer, chip, package, module/board)	Q3 2024 based on out- standing collaborations; more than 40 iRel40 experts contributed.	Recent Advances in Microelectronics Discoelectronics Beliability Contributions from the European ECSEL U project iRel40
"iRel40 is a European o Joint Undertaking (JU)	co-funded innovation project that h under grant agreement No <u>87665</u>	as been granted by the ECSEL 59. The funding of the project		VINNOVA BUSINESS Verden's Innovation Agency BUSINESS Verden's Innovation Agency Finaland Verden's Innovation Agency Verden's Innovation Agency Rindesministerium Finaland Buddesministerium Finaland Budd	

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